G. Eigen, University of Bergen In collaboration w G. Dubois-Felsmann, D. Hitlin and F. Porter

al fits of the

G. Eigen, CKM12 Cincinnati, 30/09/2012

Fit Methodology

- The scan method is a frequentist-based fitting technique of the CKM matrix that makes explicit the fact that the distribution of theory uncertainties is a priori unknown
- It therefore accounts for theory uncertainties in the QCD parameters f_{Bs} , f_{bs}/f_{bd} , B_{Bs} , B_{bs}/B_{Bd} , and B_K and the CKM matrix elements V_{ub} and V_{cb} by scanning over the range in the theory uncertainty using a fixed grid or MC methods, at each scan point doing a fit based on experimental uncertainties only
- Typically, we combine measurements of Δm_d , Δm_s , ϵ_K , V_{cb} , V_{ub} , V_{us} , V_{ud} , sin2 β , α , and γ in the χ^2
- We constrain the mean values of the QCD parameters η_{cc} , η_{ct} , η_{tt} , and η_b to their predicted values with Gaussian functions in which the width is fixed to the "statistical" uncertainty obtained from the lattice \rightarrow yields the terms (T_n) in the χ^2



The ensemble of acceptable fits is used to define a 95% CL range in the unitarity triangle parameters G. Eigen, CKM12 Cincinnati, 30/09/2012

Fit Methodology

For each point in the theory parameter space we minimize the function

$$p_{i} \text{ are parameters} \\ (A, \lambda_{3}, ...), \\ t_{m} \text{ are QCD parameters} \\ M_{k} \text{ are measurements} \\ + \left(\frac{\left\langle \left| \varepsilon_{k} \right| \right\rangle - \left| \varepsilon_{k} \right| \left(A, \bar{\rho}, \bar{\eta}; \boldsymbol{p}_{i}, \boldsymbol{t}_{m}\right)}{\sigma_{a}} \right)^{2} + \left(\frac{\left\langle \left| \varepsilon_{k} \right| \right\rangle - \left| \varepsilon_{k} \right| \left(A, \bar{\rho}, \bar{\eta}; \boldsymbol{p}_{i}, \boldsymbol{t}_{m}\right)}{\sigma_{\varepsilon}} \right)^{2} + \left(\frac{\left\langle \left| \varepsilon_{k} \right| \right\rangle - \left| \varepsilon_{k} \right| \left(A, \bar{\rho}, \bar{\eta}; \boldsymbol{p}_{i}, \boldsymbol{t}_{m}\right)}{\sigma_{\varepsilon}} \right)^{2} + \left(\frac{\left\langle \left| \varepsilon_{k} \right| \right\rangle - \sin 2\beta(\bar{\rho}, \bar{\eta}; \boldsymbol{p}_{i})}{\sigma_{sin2\beta}} \right)^{2} + \sum_{k} \left(\frac{\left\langle \mathcal{M}_{k} \right\rangle - \mathcal{M}_{k}(\boldsymbol{p}_{i})}{\sigma_{\mathcal{M}_{k}}} \right)^{2} + \left(\frac{\left\langle \left| \varepsilon_{k} \right| \right\rangle - \left| \varepsilon_{k} \right| \left(A, \bar{\rho}, \bar{\eta}; \boldsymbol{p}_{i}, \boldsymbol{t}_{m}\right)}{\sigma_{\varepsilon}} \right)^{2} + \left(\frac{\left\langle \left| \varepsilon_{k} \right| \right\rangle - \sin 2\beta(\bar{\rho}, \bar{\eta}; \boldsymbol{p}_{i})}{\sigma_{\mathcal{M}_{k}}} \right)^{2} + \sum_{k} \left(\frac{\left\langle \mathcal{M}_{k} \right\rangle - \mathcal{M}_{k}(\boldsymbol{p}_{i})}{\sigma_{\mathcal{M}_{k}}} \right)^{2} + \sum_{k} \left(\frac{\left\langle \left| \varepsilon_{k} \right| \right\rangle - \left| \varepsilon_{k} \left| \left(A, \bar{\rho}, \bar{\eta}; \boldsymbol{p}_{i}, \boldsymbol{\tau}_{m}\right)}{\sigma_{\varepsilon}} \right)^{2} + \left(\frac{\left\langle \left| \varepsilon_{k} \right| \right\rangle - \left| \varepsilon_{k} \left| \left(A, \bar{\rho}, \bar{\eta}; \boldsymbol{p}_{i}, \boldsymbol{\tau}_{m}\right)}{\sigma_{\varepsilon}} \right)^{2} + \left(\frac{\left\langle \left| \varepsilon_{k} \right| \right\rangle - \left\langle \varepsilon_{k} \right| \left\langle \left| \varepsilon_{k} \right| \right\rangle - \left\langle \varepsilon_{k} \right| \left\langle \varepsilon_{k} \right| \left\langle \varepsilon_{k} \right| \right\rangle - \left\langle \varepsilon_{k} \right| \left$$

We add measurements for m_t, m_c, B masses, B lifetimes, other CKM matrix elements to account for possible correlations

• The region encompassing all accepted fits in the \overline{p} - $\overline{\eta}$ plane then defines the range at 95% CL of parameters compatible with the CKM ansatz without assumption as to the distribution of the theory uncertainties

The contours of all accepted fits are overlaid

Ne also study correlations among the theory parameters

Fit Methodology

For illustrative purpose we show the overlay a few contours



Inputs for Comparing Different Methods

- We use the legacy book inputs to compare our results with those from CKMfitter and UTFIT
- Note that V_{ub} and V_{cb} has only an experimental uncertainty
 no scanning over these parameters here
- α and γ are input here by by their central values and uncertainty

68% CL contours

| Observable | Value |
|------------------------------|---------------------------------|
| m _t | 174.65±0.11 Gev/c ² |
| m _c | 1.29±0.11 Gev/c ² |
| <i>m_c</i> [PDG12] | 1.275±0.025 Gev/c ² |
| Δm_d | 0.507±0.004 ps ⁻¹ |
| Δm_s | 17.70±0.08 ps ⁻¹ |
| € _K | (2.228±0.0011)*10 ⁻³ |
| V _{cb} | (4.06±0.13)*10 ⁻² |
| V_{ub} | (3.89±0.44)*10 ⁻³ |
| V _{us} | 0.2254±0.0009 |
| V_{ud} | 0.97427±0.00021 |
| sin2β | 0.676±0.02 |
| α[°] | 90±5 |
| γ[°] | 76±10 |



Inputs for Comparing Different Methods

- We use the lattice QCD parameters given by the lattice group before the ICHEP 2012 conference
- The η parameters are not scanned but are treated with Gaussian uncertainties (we retain the possibility of scanning them as well)

• Parameterize η_{cc} and its uncertainties in terms of m_c and α_s

So here we scan over B_K, f_{Bs} and f_{Bs}/f_{Bd} only

| Observable | Value |
|----------------------------------|-------------------|
| f _{Bs} [MeV] | 250±5.4±11 |
| f _{Bs} /f _{Bd} | 1.215±0.012±0.015 |
| B _{Bs} | 1.33±0.06 |
| B_{Bs}/B_{Bd} | 1.05±0.07 |
| Β _κ | 0.737±0.006±0.020 |
| η _{cc} | 1.39±0.35 |
| η _{tc} | 0.5765±0.0065 |
| η _{tt} | 0.47±0.04 |
| η _b | 0.551±0.007 |



Our Fit Results for 68% Contours

- First, we test the performance wrt CKMfitter and Utfit fitting 19 measurements (V_{ud} , V_{us} , V_{cb} , V_{ub} , ε_K , Δm_d , Δm_s , sin 2 β , α , γ , f_{Bs} , B_{Bs} , f_{Bs}/f_{Bd} , B_{Bs}/B_{bd} , B_K , m_t , m_c , τ_{Bd} , τ_{Bs}) with 13 parameters (ρ , η , A, λ , f_{Bs} , B_{Bs} , f_{Bs}/f_{Bd} , B_{Bs}/B_{bd} , B_K , m_t , m_c , τ_{Bd} , τ_{Bs})
 - For fits with $P(\chi^2)>32\%$, we plot 1σ contours in the $\overline{\rho}-\overline{\eta}$ plane \rightarrow plot shows the overlay of all individual contours of accepted fits



Comparison with CKMfitter & UTfit

- The allowed region is the envelope of all accepted contours
- All 3 methods yield similar results at 68% CL
- We redo the fits by separating experimental uncertainties from theory uncertainties in V_{ub} and V_{ub} using the approach in (arXiv: 0806.0530)

| Parameter | Scan method | Scan m. (V _{ub} ,V _{cb}) | CKMfitter | UTfit |
|-------------------|---|---|-------------|-------------|
| $\overline{ ho}$ | 0.121 ^{+0.015} -0.025 | 0.132 ^{+0.027} -0.06 | 0.121±0.02 | 0.125±0.022 |
| $\overline{\eta}$ | 0.351 ^{+0.015} -0.012 | 0.359 ^{+0.025} -0.025 | 0.349±0.012 | 0.347±0.014 |
| β[°] | 21.8 ^{+0.6} -0.7 | 22.5 ^{+0.4} -1.3 | 21.7±1 | 21.6±0.8 |
| α[°] | 87.2 ^{+2.3} -4.0 | 87.7 ^{+9.2} _{-5.3} | 87.5±3.2 | 87.9±3.4 |
| γ[°] | 71.0 ^{+4.1} _{-2.2} | 69.8 ^{+9.8} -4.6 | 70.9±3.2 | 70.4±3.4 |

• Central value is that with highest $P(\chi^2)$ uncertainties are maximum & minimum values of the envelope of all contours

V_{cb} 0.0406±0.006±0.011 V_{ub} 0.00389±0.0001±0.0048

8

Results with Scanning over Vub and Vcb

• Now we redo the same fits but we scan over V_{ub} and V_{cb} in addition



The allowed \overline{p} - $\overline{\eta}$ region now increases by a factor of ~ 2



New Fit Inputs

Since ICHEP some inputs have changed

| Observable | Value | Observable | Value |
|-----------------|-------------------------------------|----------------------------------|-----------------------|
| V _{cb} | (4.1±0.0069±0.009)*10 ⁻² | f _{Bs} [MeV] | 227.6±2.2±4.5 |
| V_{ub} | (4.14±0.31±0.39)*10-3 | f _{Bs} /f _{Bd} | 1.201±0.012±0.012 |
| sin2β | 0.676±0.02 | B _{Bs} | 1.33±0.018±0.06 |
| α[°] | 90+2.2-2.1 our inputs | B _{Bs} /B _{Bd} | 1.05±0.025±0.07 |
| γ [°] | 76.4+4.1-3.8 _ see later | Β _κ | 0.7643±0.0034±0.00908 |

V_{ub} and V_{cb} are taken from PDG 2012 but we separate theory from experimental uncertainties (provided by R. Kowalewski)
 Note: V_{ub} and V_{cb} is an average over barely consistent inclusive & exclusive results that include scale factors of 2.6 and 2, respectively

α is extracted by fitting all measured branching fractions, CP
 asymmetries, S and C amplitudes for time dependent results

• γ is extracted from GLW, ADS and Dalitz plot analyses in $B \rightarrow D^{(*)}K$, $B \rightarrow DK^*$, $B \rightarrow D^{(*)}\pi$, $B \rightarrow D^{(*)}\rho$ (combine γ and sin($2\beta + \gamma$) measurements)

CKM Fits with Updated Inputs

- Fit 23 measurements with updated inputs (no B(B →τ ν)) and and 13 fit parameters
- Plot a 95% CL contour for each accepted fit



About 37% of all points in the theory parameter space give successful fits

G. Eigen, CKM12 Cincinnati, 30/09/2012

Global Fits of the CKM matrix

Same fits but include now B(B →τν)=(1.66±0.33)×10⁻⁴ (HFAG)
 (24 measurements and 13 fit parameters)

does not include new Belle measurement



95% CL contours

The number of successful fits is now reduced by another factor of 3

Global Fits of the CKM matrix

Same fits but include now B(B→τν)=(1.66±0.33)×10⁻⁴ (HFAG)
 (24 measurements and 13 fit parameters)

does not include new Belle measurement



95% CL contours

The number of successful fits is now reduced by another factor of 3

Results with and without $\mathcal{B}(B \rightarrow \tau v)$

- $\mathcal{B}(B \rightarrow \tau v)$ reduces allowed region in the $\overline{\rho} \eta$ plane \rightarrow allowed region is still quite large
- Overall fit probability becomes worst, loose about half of the previously successful fits

| Parameter | Scan-fit w/o <i>B→τ</i> ν | Scan-fit w <i>B→τν</i> | |
|-------------------|---------------------------|------------------------|------------------|
| $\overline{ ho}$ | 0.071—0.148 | 0.082—0.14 | (95% CL regions) |
| $\overline{\eta}$ | 0.314—0.393 | 0.327—0.387 | |
| β[°] | 19.2—24.1 | 20.0—23.7 | |
| α[°] | 80.5—91.1 | 81.7—89.7 | |
| γ[°] | 67.6—78.1 | 68.7—76.6 | |



The 95% CL regions in ρ-η are maximum and minimum values of the envelope of all contours, the 95% CL regions on the angles are calculated from the ρ-η values G. Eigen. CKM12 Cincinnati. 30/09/2012

Fits to Extract Angles

- ♥ We fit branching fractions, CP asymmetries, S & C of time-dependent asymmetries of all measured b→uūd and b→uūs modes to determine y
- Following the Gronau-Rosner approach, the amplitudes are parameterized in terms of tree, color-suppressed tree, penguin, singlet penguin, W-annihilation/W-exchange, electroweak and colorsuppressed electroweak diagrams (up to λ³ beyond leading order)
- For $b \rightarrow u\overline{u}s$ modes, SU(3) breaking is included for penguin, tree, colorsuppressed tree and singlet penguin amplitudes (suppressed by λ)
- For $B \rightarrow PP$ modes, we use 42 measurement to fit 20 parameters
- For $B \rightarrow PV$ modes, we use 69 measurement to fit 35 parameters
- For $B \rightarrow VV$ modes, we use 52 measurement to fit 34 parameters
- For all modes combined including 17 $B \rightarrow a_1 P$ measurements and 13 parameters, we fit a total of 173 measurements with 92 parameters ($P(\chi^2)=10\%$)

Note that no V_{ub} , V_{cb} and sin 2 β measurements are used here G. Eigen, CKM12 Cincinnati, 30/09/2012

Fits to Extract α



Fits to extract γ

- Use all available GLW, ADS and Dalitz plot measurements in $B \rightarrow D^{(*)}K$, $B \rightarrow DK^*$, $B \rightarrow D^{(*)}\pi$, $B \rightarrow DK^*$ and the sin($2\beta + \gamma$) results from $B \rightarrow D^{(*)}\pi$ and $B \rightarrow D\rho$ time-dependent analyses
- Parameterize measurements in terms of $r=|A(b\rightarrow u)/A(b\rightarrow c)|$ separating out CKM factor and strong phase
- Use 56 measurements to extract 19 fit parameters, constrain $V_{us}V_{ub}^*/V_{cs}V_{cb}^*$ and $V_{ud}V_{ub}^*/V_{cd}V_{cb}^*$ to measured ratios (central values) $\rightarrow P(\chi^2)=6\%$
- β extracted in this approach is higher than that from the sin 2β measurements

| Mode | γ [±1σ] | β[±1σ] |
|------|--------------------------------------|------------|
| all | 1.33 ^{+0.072} -0.066 | 0.46±0.029 |
| G | Figen CKM12 Cincinnati | 30/09/2012 |



Scan over V_{ub} and V_{cb} shows $\beta - V_{ub} / V_{cb}$ correlation



Conclusions

- For the same inputs the three fitting methods yield similar results, even with a scan over B_K , f_{Bs} and f_{Bs}/f_{Bd}
- Due to the discrepancy between inclusive and exclusive V_{ub} and V_{cb} measurements theory uncertainties are sizable and scanning over them increases the allowed region in the ρ - η plane significantly
- Measurements of Δm_d, Δm_s, ε_K, V_{cb}, V_{ub}, other CKM parameters, sin2β, α, and γ are in good agreement with the SM, even the inclusion of B[±] →τ[±] ν measurements reduces the allowed region in the ρ-η plane
 number of successful fits decreases by 2/3
- Consistent with the Standard Model at the 10% level → yield a precise measurement of α (correlations between α and β are small)
- All GLW, ADS and Dalitz plot measurements in $B \rightarrow D^{(*)}K$, $B \rightarrow DK^*$, $B \rightarrow D^{(*)}\pi$, $B \rightarrow DK^*$ and the sin($2\beta + \gamma$) results from $B \rightarrow D^{(*)}\pi$ and $B \rightarrow D\rho$ time-dependent analyses are in agreement with the Standard Model \rightarrow yield a precise measurement of γ

Conclusions

- With this method, making no assumptions about the distribution of theory errors within specified ranges, there is no tension with the Standard Model
- As long as there acceptable fits within the broad region of reasonable values of theory parameters, we find consistency with the SM

